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With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



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EPC2040 eGaN® FET DATASHEET

## **EPC2040 – Enhancement Mode Power Transistor**

 $V_{\rm DSS}$ , 15 V  $R_{DS(on)}$ , 30 m $\Omega$  $\overline{I_D}$ , 3.4 A

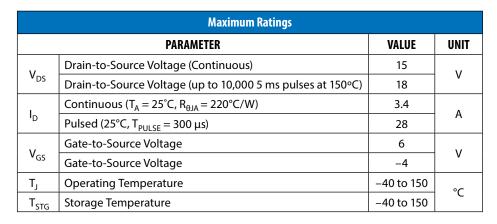








Gallium Nitride is grown on Silicon Wafers and processed using standard CMOS equipment leveraging the infrastructure that has been developed over the last 60 years. GaN's exceptionally high electron mobility and low temperature coefficient allows very low  $R_{DS(on)}$ , while its lateral device structure and majority carrier diode provide exceptionally low  $Q_G$  and zero  $Q_{RR}$ . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.





EPC2040 eGaN® FETs are supplied only in passivated die form with solder bumps Die Size: 0.85 mm x 1.25 mm

### **Applications**

- High Speed DC-DC conversion
- LiDAR/Pulsed Power Applications
- LiDAR for Augmented Reality Applications

#### **Benefits**

- · Ultra High Efficiency
- Ultra Low R<sub>DS(on)</sub>
- Ultra Low Q<sub>G</sub>
- Ultra Small Footprint

www.epc-co.com/epc/Products/eGaNFETs/EPC2040.aspx

Static Characteristics (T <sub>J</sub> = 25°C unless otherwise stated)						
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$BV_{DSS}$	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V, I}_{D} = 300 \mu\text{A}$	15			V
I <sub>DSS</sub>	Drain-Source Leakage	$V_{DS} = 12 \text{ V}, V_{GS} = 0 \text{ V}$		10	250	mA
I <sub>GSS</sub>	Gate-to-Source Forward Leakage	$V_{GS} = 5 \text{ V}$		0.1	1.2	mA
	Gate-to-Source Reverse Leakage	V <sub>GS</sub> = -4 V		10	250	mA
V <sub>GS(TH)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 1 \text{ mA}$	0.8	1.4	2.5	V
R <sub>DS(on)</sub>	Drain-Source On Resistance	$V_{GS} = 5 \text{ V, I}_{D} = 1.5 \text{ A}$		24	30	mΩ
$V_{SD}$	Source-Drain Forward Voltage	$I_S = 0.5 \text{ A}, V_{GS} = 0 \text{ V}$		2.2		V

All measurements were done with substrate shorted to source.

Thermal Characteristics				
	PARAMETER TYP UNI			
R <sub>ØJC</sub>	Thermal Resistance, Junction-to-Case	5.7		
R <sub>ØJB</sub>	Thermal Resistance, Junction-to-Board	19	°C/W	
$R_{\emptyset JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	97		

Note 1:  $R_{BJA}$  is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See http://epc-co.com/epc/documents/product-training/Appnote\_Thermal\_Performance\_of\_eGaN\_FETs.pdf for details

<b>Dynamic Characteristics (T</b> <sub>J</sub> = 25°C unless otherwise stated)						
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
C <sub>ISS</sub>	Input Capacitance			86	105	
C <sub>RSS</sub>	Reverse Transfer Capacitance	$V_{DS} = 6 \text{ V}, V_{GS} = 0 \text{ V}$		20		
C <sub>OSS</sub>	Output Capacitance			67	100	pF
C <sub>OSS(ER)</sub>	Effective Output Capacitance, Energy Related (Note 2)	V 0+- (VV 0V		106		
C <sub>OSS(TR)</sub>	Effective Output Capacitance, Time Related (Note 3)	$V_{DS} = 0$ to 6 V, $V_{GS} = 0$ V		87		
$R_G$	Gate Resistance			0.5		Ω
$Q_{G}$	Total Gate Charge	$V_{DS} = 6 \text{ V}, V_{GS} = 5 \text{ V}, I_{D} = 1.5 \text{ A}$		745	925	
$Q_{GS}$	Gate to Source Charge			230		
$Q_{GD}$	Gate to Drain Charge	$V_{DS} = 6 \text{ V}, I_{D} = 1.5 \text{ A}$		140		
Q <sub>G(TH)</sub>	Gate Charge at Threshold			165		pC
Q <sub>OSS</sub>	Output Charge	$V_{DS} = 6 \text{ V}, V_{GS} = 0 \text{ V}$		420	630	
Q <sub>RR</sub>	Source-Drain Recovery Charge			0		

Note 2:  $C_{OSS(ER)}$  is a fixed capacitance that gives the same stored energy as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 50%  $BV_{DSS}$ . Note 3:  $C_{OSS(TR)}$  is a fixed capacitance that gives the same charging time as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 50%  $BV_{DSS}$ .

Figure 1: Typical Output Characteristics at 25°C

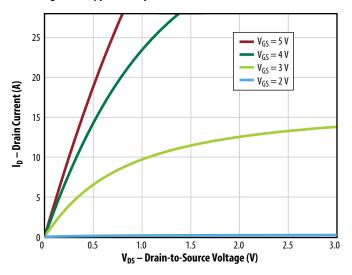


Figure 3:  $R_{\text{DS(on)}}\,\text{vs.}\,V_{\text{GS}}$  for Various Drain Currents

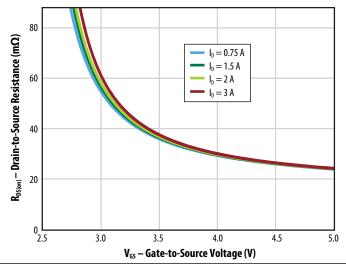


Figure 2: Transfer Characteristics

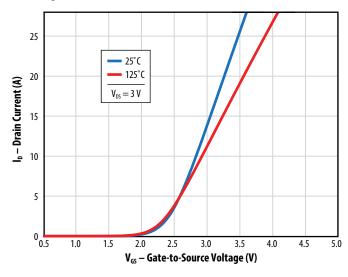


Figure 4: R<sub>DS(on)</sub> vs. V<sub>GS</sub> for Various Temperatures

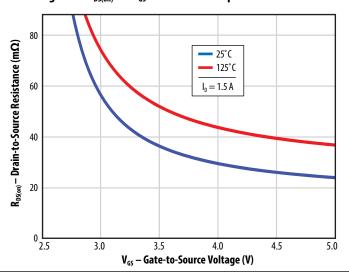


Figure 5a: Capacitance (Linear Scale)

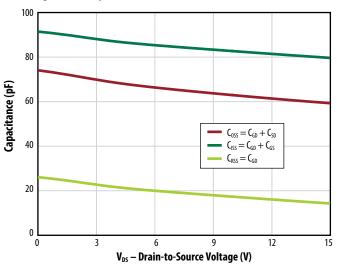


Figure 5b: Capacitance (Log Scale)

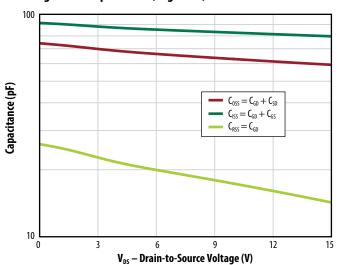
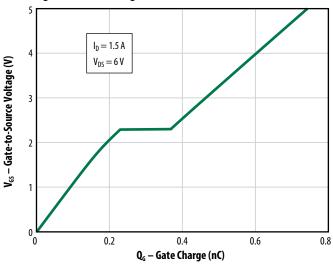


Figure 6: Gate Charge



**Figure 7: Reverse Drain-Source Characteristics** 

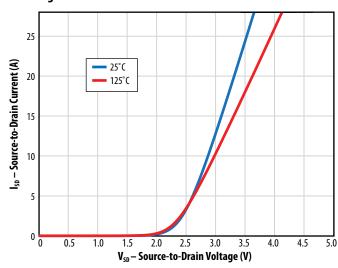


Figure 8: Normalized On-State Resistance vs. Temperature

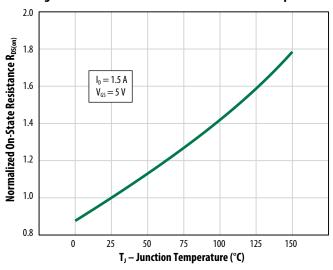
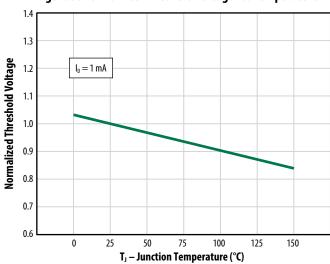
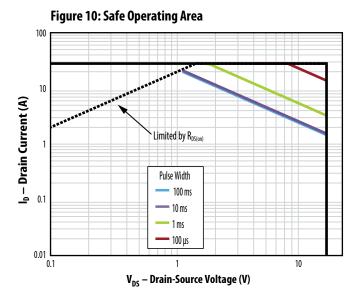


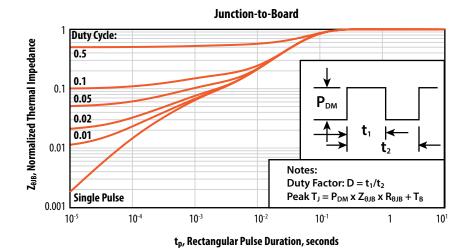
Figure 9: Normalized Threshold Voltage vs. Temperature

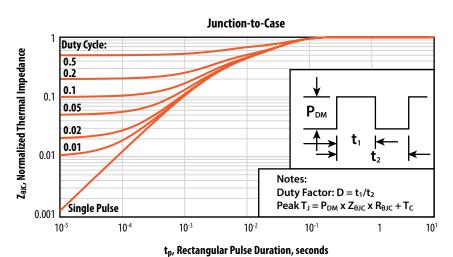


All measurements were done with substrate shortened to source.

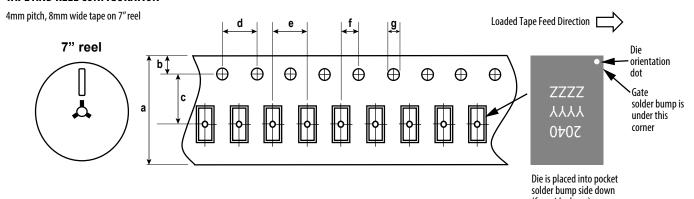


**Figure 11: Transient Thermal Response Curves** 





### **TAPE AND REEL CONFIGURATION**



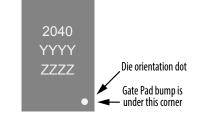
	EPC2040 (note 1)			
Dimension (mm)	target	min	max	
а	8.00	7.90	8.30	
b	1.75	1.65	1.85	
c (see note)	3.50	3.45	3.55	
d	4.00	3.90	4.10	
е	4.00	3.90	4.10	
f (see note)	2.00	1.95	2.05	
g	1.5	1.5	1.6	

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/JEDEC industry standard.

Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

### **DIE MARKINGS**

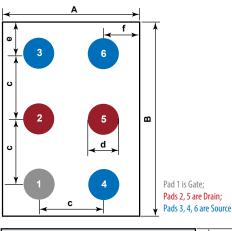
Part	Laser Markings			
Number	Part # Marking Line 1	Lot_Date Code Marking line 2	Lot_Date Code Marking line 3	
EPC2040	2040	YYYY	ZZZZ	



(face side down)

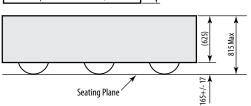
#### **DIE OUTLINE**

**Solder Bump View** 



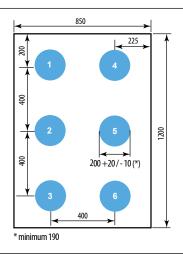
	Micrometers			
DIM	MIN	Nominal	MAX	
Α	820	850	880	
В	1170	1200	1230	
C		400		
d	187	208	229	
e	185	200	215	
f	210	225	240	

Side View



### RECOMMENDED **LAND PATTERN**

(measurements in  $\mu$ m)



Solder mask opening

200 μm

The land pattern is solder mask defined Solder mask is 10 µm smaller per side than bump

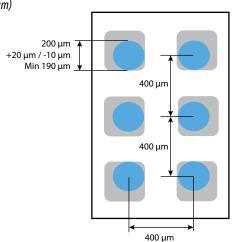
Pad 1 is Gate;

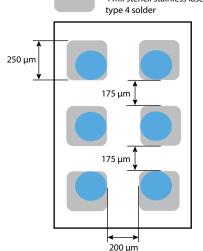
Pads 2, 5 are Drain;

Pads 3, 4, 6 are Source

## **RECOMMENDED STENCIL DRAWING**

(measurements in  $\mu$ m)





Stencil opening

250 μm rounded square (60 deg) 4 mil stencil stainless laser cut

> Recommended stencil should be 4 mil (100 µm) thick, must be laser cut, openings per drawing.

Intended for use with SAC305 Type 4 solder, reference 88.5% metals content.

Additional assembly resources available at http://epc-co.com/epc/DesignSupport/ AssemblyBasics.aspx

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Information subject to change without notice.

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